MOSFET – Power, Single N-Channel

40 V, 52 A, 7.3 mΩ

NTMYS7D3N04CL

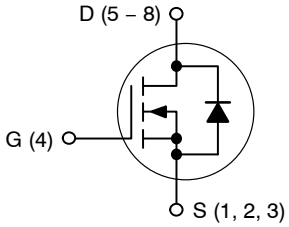
$V_{(BR)DSS}$	$R_{DS(on)}$ MAX	I_D MAX
40 V	7.3 mΩ @ 10 V	52 A
	12 mΩ @ 4.5 V	

LFPAK4
CASE 760AB

Features

- Small Footprint (5x6 mm) for Compact Design
- Low $R_{DS(on)}$ to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- LFPAK4 Package, Industry Standard
- These Devices are Pb−Free and are RoHS Compliant

N−Channel



MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Symbol	Parameter			Value	Unit
V_{DSS}	Drain−to−Source Voltage			40	V
V_{GS}	Gate−to−Source Voltage			±20	V
I_D	Continuous Drain Current $R_{\theta JC}$ (Notes 1, 2, 3, 4)	Steady State	T_C = 25°C	52	A
			T_C = 100°C	29	
P_D	Power Dissipation $R_{\theta JC}$ (Notes 1, 2, 3)		T_C = 25°C	38	W
			T_C = 100°C	12	
I_D	Continuous Drain Current $R_{\theta JA}$ (Notes 1 & 3, 4)	Steady State	T_A = 25°C	17	A
			T_A = 100°C	12	
P_D	Power Dissipation $R_{\theta JA}$ (Notes 1, 3)		T_A = 25°C	3.8	W
			T_A = 100°C	1.9	
I_{DM}	Pulsed Drain Current	T_A = 25°C, t_p = 10 μs		269	A
T_J, T_{stg}	Operating Junction and Storage Temperature			−55 to +175	°C
I_S	Source Current (Body Diode)			31	A
E_{AS}	Single Pulse Drain−to−Source Avalanche Energy ($I_{L(pk)}$ = 2.9 A)			65	mJ
T_L	Lead Temperature for Soldering Purposes (1/8″ from case for 10 s)			260	°C

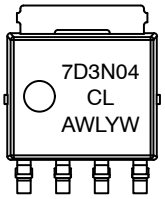
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Junction−to−Case − Steady State (Note 3)	4.0	°C/W
$R_{\theta JA}$	Junction−to−Ambient − Steady State (Note 3)	39	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
2. Psi (Ψ) is used as required per JESD51−12 for packages in which substantially less than 100% of the heat flows to single case surface.
3. Surface−mounted on FR4 board using a 650 mm^2, 2 oz. Cu pad.
4. Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

MARKING DIAGRAM



7D3N04CL	= Specific Device Code
A	= Assembly Location
WL	= Wafer Lot
Y	= Year
W	= Work Week

ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Condition		Min	Typ	Max	Unit
OFF CHARACTERISTICS							
$V_{(BR)DSS}$	Drain−to−Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 μA		40			V
$V_{(BR)DSS}/T_J$	Drain−to−Source Breakdown Voltage Temperature Coefficient				25		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{GS} = 0 V, V_{DS} = 40 V	T_J = 25°C			10	μA
			T_J = 125°C			250	
I_{GSS}	Gate−to−Source Leakage Current	V_{DS} = 0 V, V_{GS} = 20 V				100	nA
ON CHARACTERISTICS (Note 5)							
$V_{GS(TH)}$	Gate Threshold Voltage	V_{GS} = V_{DS}, I_D = 30 μA		1.2		2.0	V
$R_{DS(on)}$	Drain−to−Source On Resistance	V_{GS} = 10 V, I_D = 10 A			6.1	7.3	mΩ
		V_{GS} = 4.5 V, I_D = 10 A			9.7	12	
g_{FS}	Forward Transconductance	V_{DS} = 15 V, I_D = 10 A			33		S
CHARGES AND CAPACITANCES							
C_{iss}	Input Capacitance	V_{GS} = 0 V, f = 1.0 MHz, V_{DS} = 25 V			860		pF
C_{oss}	Output Capacitance				360		
C_{rss}	Reverse Transfer Capacitance				15		
$Q_{G(TOT)}$	Total Gate Charge	V_{GS} = 4.5 V, V_{DS} = 32 V, I_D = 10 A			7.0		nC
$Q_{G(TH)}$	Threshold Gate Charge	V_{GS} = 10 V, V_{DS} = 32 V, I_D = 10 A			1.8		nC
Q_{GS}	Gate−to−Source Charge				3.3		
Q_{GD}	Gate−to−Drain Charge				2.5		
$Q_{G(TOT)}$	Total Gate Charge	V_{GS} = 10 V, V_{DS} = 32 V, I_D = 10 A			16		nC
SWITCHING CHARACTERISTICS (Note 6)							
$t_{d(on)}$	Turn−On Delay Time	V_{GS} = 10 V, V_{DS} = 32 V, I_D = 10 A, R_G = 1 Ω			8.0		ns
t_r	Rise Time				24		
$t_{d(off)}$	Turn−Off Delay Time				29		
t_f	Fall Time				6.0		
DRAIN−SOURCE DIODE CHARACTERISTICS							
V_{SD}	Forward Diode Voltage	V_{GS} = 0 V, I_S = 10 A	T_J = 25°C		0.84	1.2	V
			T_J = 125°C		0.71		
t_{RR}	Reverse Recovery Time	V_{GS} = 0 V, dI_S/dt = 100 A/μs, I_S = 10 A			24		ns
t_a	Charge Time				11		
t_b	Discharge Time				12		
Q_{RR}	Reverse Recovery Charge				11		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

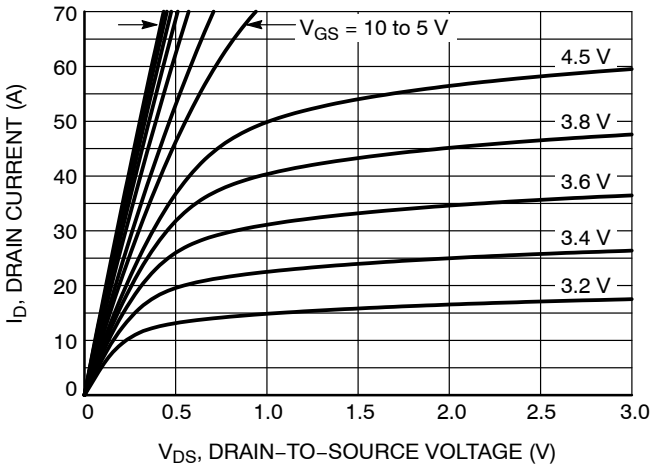


Figure 1. On−Region Characteristics

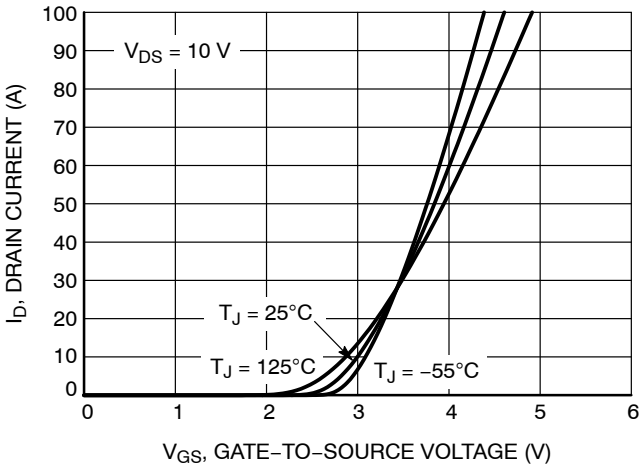


Figure 2. Transfer Characteristics

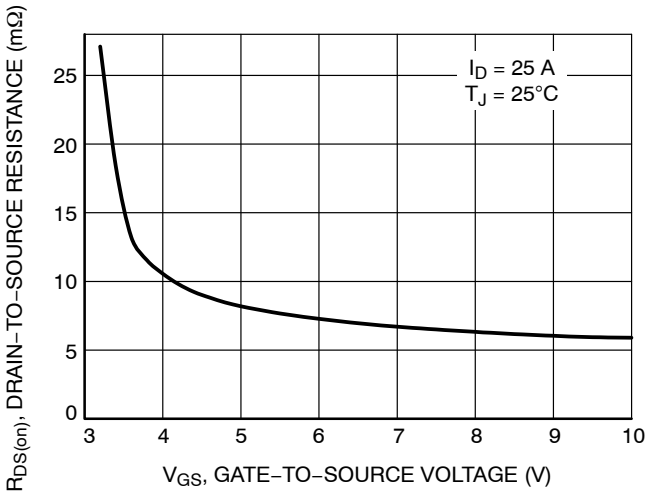


Figure 3. On−Resistance vs. Gate−to−Source Voltage

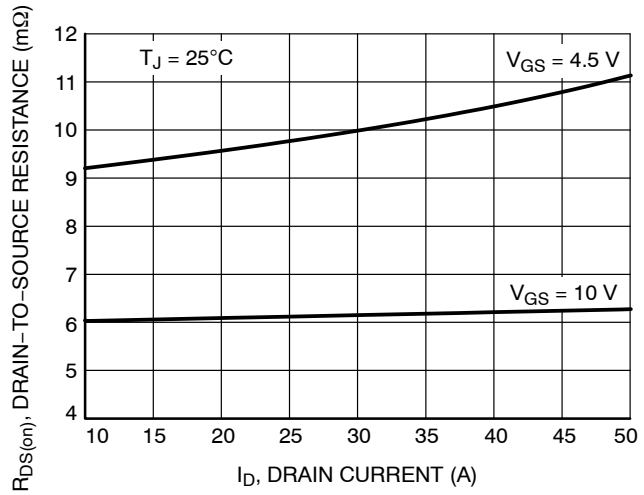


Figure 4. On−Resistance vs. Drain Current and Gate Voltage

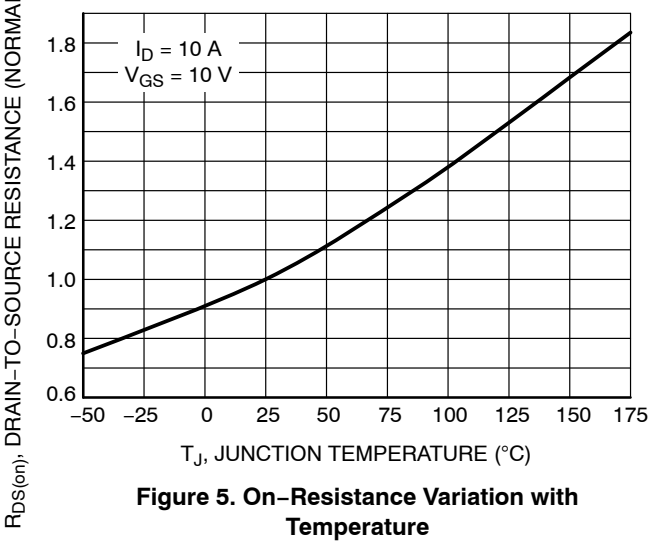


Figure 5. On−Resistance Variation with Temperature

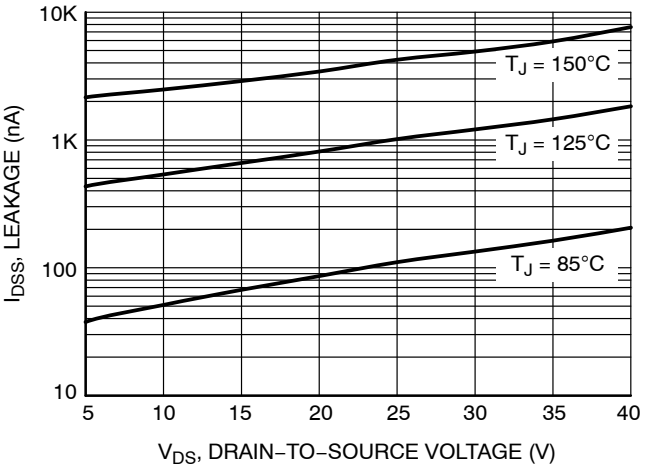


Figure 6. Drain−to−Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS (continued)

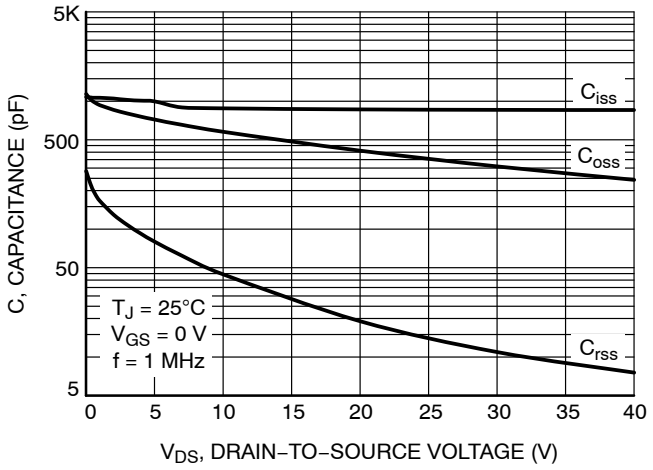


Figure 7. Capacitance Variation

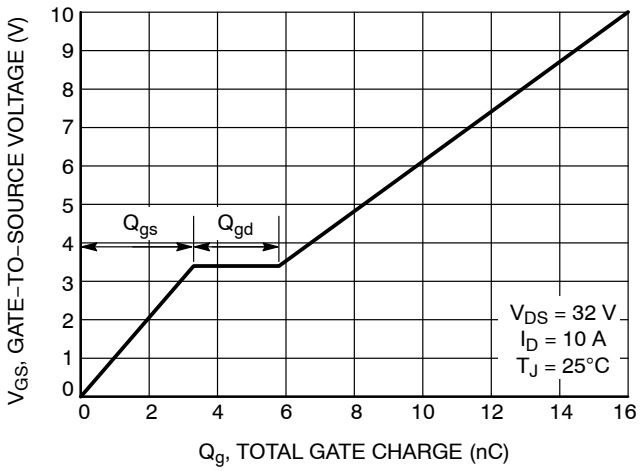


Figure 8. Gate−to−Source vs. Total Charge

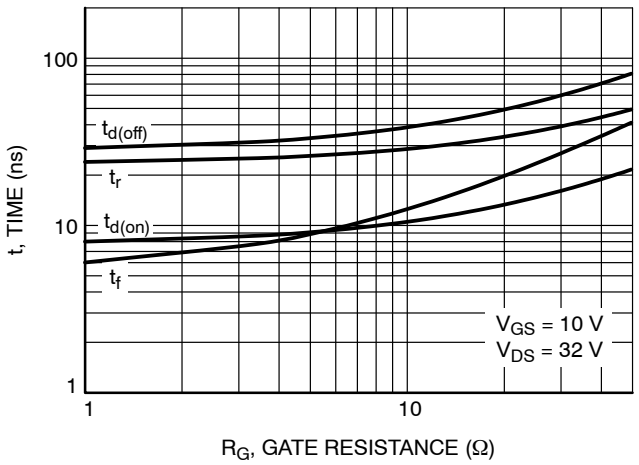


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

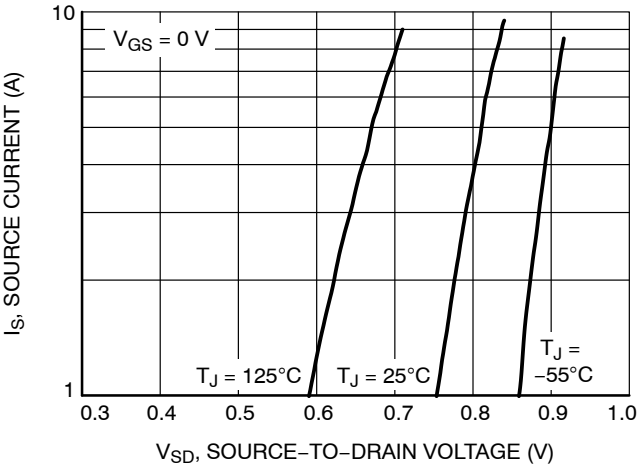


Figure 10. Diode Forward Voltage vs. Current

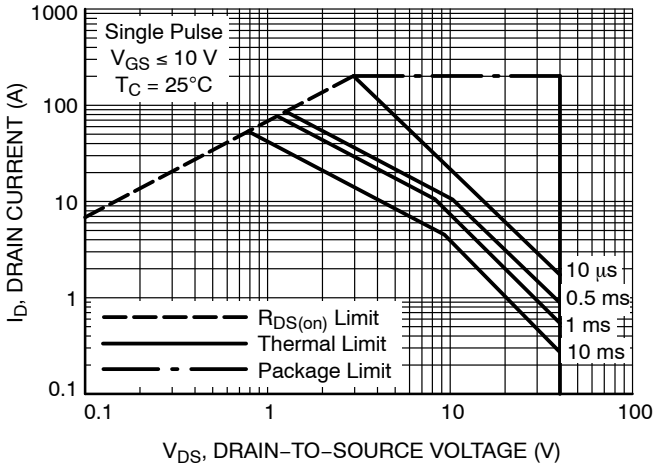


Figure 11. Maximum Rated Forward Biased Safe Operating Area

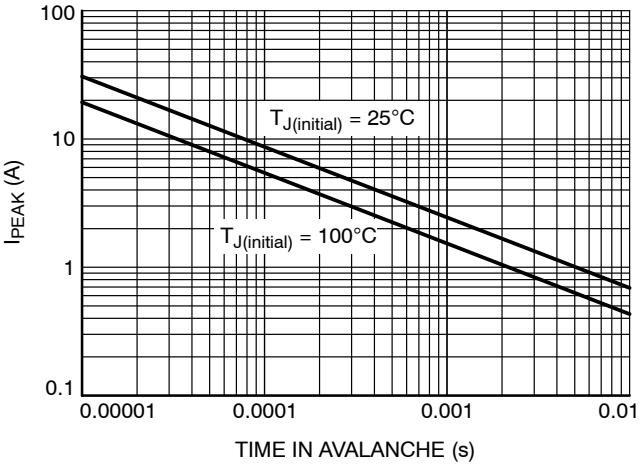


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS (continued)

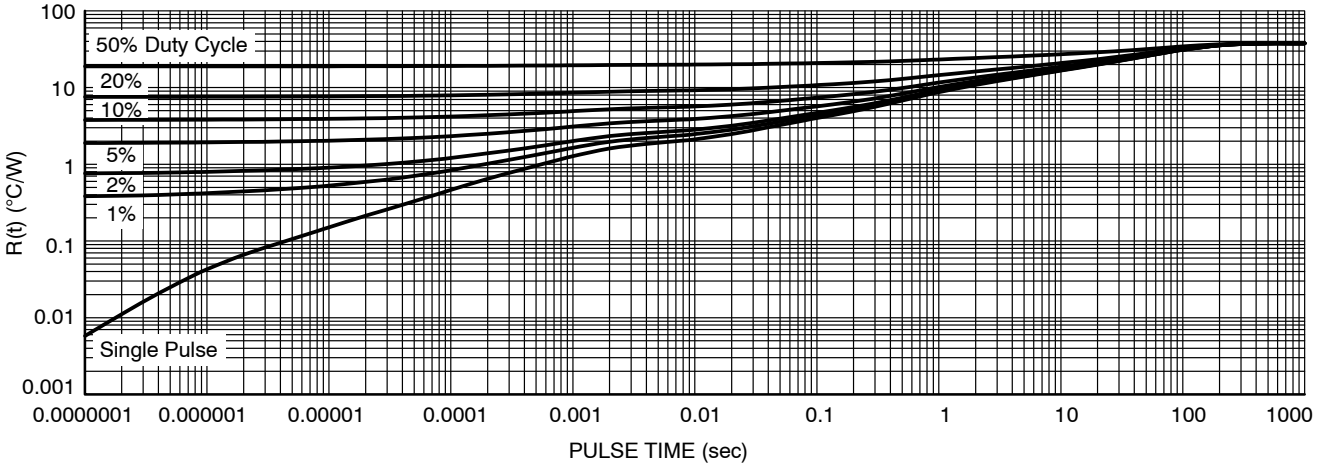


Figure 13. Thermal Characteristics

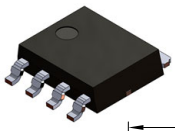
DEVICE ORDERING INFORMATION

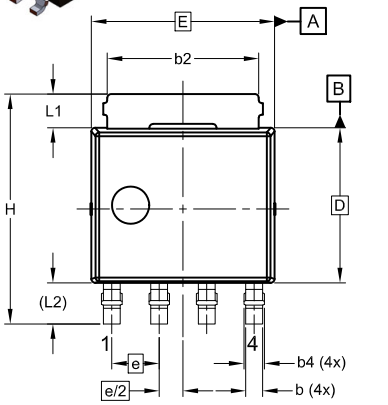
Device	Marking	Package	Shipping†
NTMYS7D3N04CLTWG	7D3N04CL	LFPAK4 (Pb−Free)	3,000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

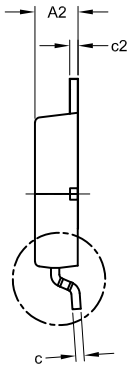
LFPAK4 4.90x4.15x1.15MM, 1.27P
CASE 760AB
ISSUE D

DATE 22 MAY 2024



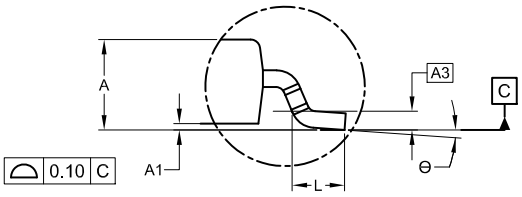


TOP VIEW

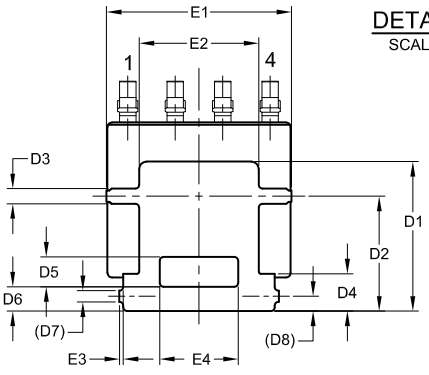


SIDE VIEW

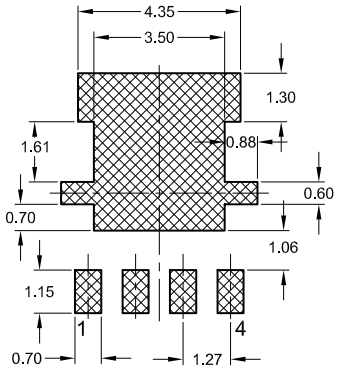
NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2018.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
4. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.



DETAIL 'A'
SCALE: 2:1



BOTTOM VIEW

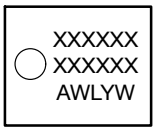


RECOMMENDED LAND PATTERN

*FOR ADDITIONAL INFORMATION ON OUR PB−FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ONSEMI SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

MILLIMETER			
DIM	MIN	NOM	MAX
A	1.10	1.20	1.30
A1	0.00	0.08	0.15
A2	1.10	1.15	1.20
A3		0.25 BSC	
b	0.40	0.45	0.50
b2	3.80	4.10	4.40
b4	0.45	0.55	0.65
c	0.19	0.22	0.25
c2	0.19	0.22	0.25
D		4.15 BSC	
D1	3.80	4.00	4.20
D2	3.00	3.10	3.20
D3	0.30	0.40	0.50
D4	0.90	1.00	1.10
D5	0.70	0.80	0.90
D6	0.55	0.65	0.75
D7		0.31 REF	
D8		0.40 REF	
E		4.90 BSC	
E1	4.85	4.95	5.05
E2	3.10	3.20	3.30
E3	0.00	0.10	0.20
E4	2.00	2.10	2.20
e		1.27 BSC	
e/2		0.635 BSC	
e1		0.40 REF	
H	6.00	6.15	6.30
L	0.50	0.70	0.90
L1	0.80	0.90	1.00
L2		1.10 REF	
Θ	0°	4°	8°

GENERIC MARKING DIAGRAM*



XXXXXX = Specific Device Code
A = Assembly Location
WL = Wafer Lot
Y = Year
W = Work Week

*This information is generic. Please refer to device data sheet for actual part marking. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	**98AON82777G**	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	**LFPAK4 4.90x4.15x1.15MM, 1.27P**		**PAGE 1 OF 1**

ADDITIONAL INFORMATION

TECHNICAL PUBLICATIONS:
Technical Library: www.onsemi.com/design/resources/technical−documentation
onsemi Website: www.onsemi.com

ONLINE SUPPORT: www.onsemi.com/support
For additional information, please contact your local Sales Representative at www.onsemi.com/support/sales